# INTERNATIONAL STANDARD

# ISO/IEC 8882-2

Second edition 1995-12-15

# Information technology — Telecommunications and information exchange between systems — X.25 DTE

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Data link layer conformance test suite

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Technologies de l'information — Télécommunications et échange d'information entre systèmes — Test de conformité X.25 DTE —

Partie 2: Suite d'essais de conformité pour la couche liaison de données



# ISO/IEC 8882-2:1995(E)

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## Foreword

ISO (the International Organization for Standardization) and IEC (the International Electrotechnical Commission) form the specialized system for worldwide standardization. National bodies that are members of ISO or IEC participate in the development on International Standards through technical committees established by the respective organization to deal with particular fields of mutual interest. Other international organizations, governmental and non-governmental, in liaison with ISO and IEC, also take part in the work.

In the field of information technology, ISO and IEC have established a joint technical ISO/IEC JTC1. Draft International Standards adopted by the joint technical committee are circulated to national bodies for voting. Publication as an International Standard requires approval by at least 75 % of the national bodies casting a vote.

International Standard ISO/IEC 8882-2 was prepared by Joint Technical Committee ISO/IEC JTC1, Information technology, Subcommittee SC 6, Telecommunications and information exchange between systems.

This second edition cancels and replaces the first edition (ISO/IEC 8882-2 1992), which has been technically revised.

ISO/IEC 8882 consists of the following parts, under the general title information technology -- Telecommunications and information exchange between systems -- X.25 DTE conformance testing: 4-1a2a-4724-99ad-d185b7e505ba/iso-iec-8882-2-1995

- Part 1 : General principles
- Part 2 : Data link layer conformance test suite
- Part 3 : Packet layer conformance test suite

Annex A of this part of IOS/IEC 8882 is for information only.

## Introduction

This part of ISO/IEC 8882 presents the X.25-DTE Conformance Test Suite for Data Link Layer, described in Tree and Tabular Combined Notation (TTCN).

Part 1 of ISO/IEC 8882 explains the objectives and usage of this part of ISO/IEC 8882.

Clause 1 of this part of ISO/IEC 8882 is the scope which provides an objective basis for the applicability of the tests within this part of ISO/IEC 8882. Clauses 2 and 3 give the references, definitions and abbreviations used in this part of ISO/IEC 8882. Clause 4 contains information relating to procedures performed in conformance testing. The test suite structure is defined in terms of test groups and subgroups in Table 1. This clause also gives an overview of the test suite. Clause 5 contains the abstract test suite for the X.25-DTE LAPB Data Link Layer protocol. Finally, Annex A provides a conformance testing summary matrix.

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# Information technology — Telecommunications and information exchange between systems — X.25 DTE conformance testing —

# Part 2:

# Data link layer conformance test suite

# 1 Scope

This part of ISO/IEC 8882 defines an abstract test suite for testing the conformance of the Data Link Layer of an IUT with respect to ISO/IEC 7776 or the CCITT Recommendation X.25 (1980, 1984).

Conformance of a Data Terminal Equipment (DTE) to the above ISO International Standard or CCITT Recommendations is tested using a dedicated circuit between the tester and the DTE. It is noted that CCITT Recommendations X.25 (1980) and X.25 (1984) are written from the perspective of a DCE and therefore do not always explicitly specify the DTE's operation. In such cases it is assumed that recommended

operation of a DTE is included by implication because of the need to communicate with X.25 DCEs. This part of ISO/IEC 8882 excludes the testing of the LAP procedures given in the CCITT Recommendations.

NOTE Test cases for extended mode operation (Modulo 128), multilink procedure and DTE-DTE operation as per ISO/IEC 7776 are for further study.

The tests in this part of ISO/IEC 8882 are designed for three possible interworking situations, shown in Figure 1. This part specifies tests for all three cases shown in Figure 1, but recognizes that not every test may apply to a particular DTE. A test selection procedure has to be performed to determine the applicability of a test to a particular DTE. Such selection will be based on the PICS and the PIXIT.

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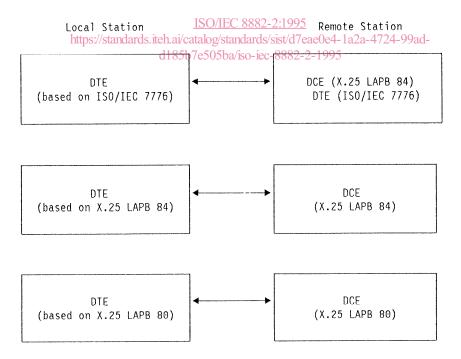


Figure 1 - Testing X.25-DTE/DCE and X.25-DTE/DTE Interworking

In the rest of this part of ISO/IEC 8882, the term "X.25 standards" means all three of CCITT Recommendation X.25 (1980), CCITT Recommendation X.25 (1984), and

International Standard ISO/IEC 7776, unless stated otherwise.

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# 2 Normative references

The following standards contain provisions which, through reference in this text, constitute provisions of this part of ISO/IEC 8882 At the time of publication, the editions indicated were valid. All standards are subject to revision, and parties to agreements based on this part of ISO/IEC 8882 are encouraged to investigate the possibility of applying the most recent editions of the standards listed below. Members of IEC and ISO maintain registers of currently valid International Standards.

ISO/IEC 7498-1: 1994, Information technology -- Open Systems Interconnection -- Basic Reference Model: The Basic Model (See also CCITT Recommendation X.200).

ISO/IEC 7776: 1995, Information technology -- Telecommunications and information exchange between systems -- High-level data link control procedures --Description of the X.25 LAPB-compatible DTE data link procedures.

ISO/IEC 8824: 1990, Information technology -- Open Systems Interconnection -- Specification of Abstract ARD PREVIEW Syntax Notation One (ASN.1) (See also CCITT Recommendation X.680). (standar

ISO/IEC 8882-1:1993, Information technology -- Telecommunications and information exchange between systems -- X.25-DTE conformance destring and Range standards is (N)-protocoladata white (NI-PDU). In the context of General principles.

ISO/IEC 9646-1: 1991, Information technology -- Open Systems Interconnection -- Conformance testing methodology and framework -- Part 1: General concepts. (See also CCITT Recommendation X.290).

ISO/IEC 9646-2: 1994, Information technology -- Open Systems Interconnection -- Conformance testing methodology and framework -- Part 2: Abstract Test Suite specification. (See also CCITT Recommendation X.291).

ISO/IEC 9646-3: 1992, Information technology -- Open Systems Interconnection -- Conformance testing methodology and framework -- Part 3: The Tree and Tabular Combined Notation (TTCN).

ISO/IEC 9646-4: 1994, Information technology -- Open Systems Interconnection -- Conformance testing methodology and framework -- Part 4: Test realization. (See also CCITT Recommendation X.293).

ISO/IEC 9646-5: 1994, Information technology -- Open Systems Interconnection -- Conformance testing methodology and framework -- Part 5: Requirements on test laboratories and clients for the conformance assessment process. (See also CCITT Recommendation X.294).

Recommendation X.25 (1980), CCITT Between Data Terminating Equipment (DTE) and Data Circuit- Terminating Equipment (DCE) for Terminals Operating in the Packet Mode on the Public Data Networks.

CCITT Recommendation X.25 (1984), Interface Between Data Terminating Equipment (DTE) and Data Circuit-Terminating Equipment (DCE) for terminals operating in the Packet Mode on the Public Data Networks by Dedicated Circuit.

## 3 Definitions and abbreviations

For the purposes of this part of ISO/IEC 8882, the definitions given in 3.4 and in the following International Standards apply:

- a) ISO/IEC 7498-1;
- b) ISO/IEC 9646;
- c) ISO/IEC 8882-1.

3.1. Reference model definitions s.item.ai

The following terms defined in ISO/IEC 7498-1 are 88845ed 004

- d185b7e505ba/iso-iec-88his2pant) of ISO/IEC 8882 (N) is layer 2 and so N-PDU is abbreviated to PDU. A PDU in the Data Link Layer is also referred to as a "frame".
  - b) Data Link Layer

## 3.2 Conformance testing terms

The following terms are used from the Conformance Testing Methodology and Framework International Standard (ISO/IEC 9646):

- a) Conformance Testing
- b) Conformance Test Suite
- c) Implementation Under Test (IUT)
- d) Protocol Implementation Conformance Statement (PICS)
- e) Protocol Implementation Extra Information for Testing (PIXIT)
- f) Static Conformance Requirements (SCR)
- g) Behavior Testing
- h) Test Purpose
- i) Tree and Tabular Combined Notation (TTCN)
- j) Preamble

- k) Test Body
- I) Test Step
- m) Test Event
- n) Abstract Service Primitive (ASP)
- o) Test Group
- p) Abstract Test Suite (ATS)
- q) Executable Test Suite (ETS)
- r) Test Verdicts
- s) Lower Tester
- t) Upper Tester
- u) Test Methods
- v) Remote Single (layer) Test Method (RS method)
- w) Valid Test Event
- x) Invalid Test Event
- y) Inopportune Test Event
- z) Point of Control and Observation (PCO)

3.3 X.25-DTE conformance testing terms

- a) it is not properly bounded by two flags;
- b) it contains fewer than 32 bits between flags;
- c) it contains a Frame Check Sequence (FCS) error;
- d) it contains an invalid address field encoding;
- e) it contains a command or response control field encoding that is undefined or not implemented in X.25-DTE LAPB Data Link Layer protocol as specified in ISO/IEC 7776;
- f) it is an I frame exceeding the maximum established frame length;
- g) it is an unnumbered or supervisory frame with an information field which is not permitted;
- h) it is a frame with an invalid N(R).
- **3.4.2** inopportune frame: A syntactically valid frame arriving at a time (DTE's state) when it should be considered irrelevant by the DTE. Syntactically valid frames are those that are allowed by the X.25 standards for a DTE using the LAPB procedure and are not covered by **3.4.1**.
- **3.4.3 proper frame :** A valid frame arriving at the correct DTE's state or phase and not covered by 3.4.1 or 3.4.2.

This part of ISO/IEC 8882 makes use of the following terms defined in ISO/IEC 8882-1:

a) Improper PDU

ISO/IEC 8882-2:1995

b) Proper PDU

https://standards.iteh.ai/catalog/standards/The/dabbreviation\_IUT4is/sused in this part of ISO/IEC d185b7e505ba/iso-iec8882/to-refer to an X.25-DTE under test.

3.5 Abbreviations

- c) Test Case
- d) Test Subgroup
- e) Tester

# 3.4 Additional definitions

This test suite uses test subgroups for proper, improper and inopportune frames to test the IUT behavior. These terms are defined below.

**3.4.1 improper frame**: A frame that satisfies one or more of the following conditions:

# 4 Test suite information

# 4.1 Test suite structure

The X.25-DTE Data Link Layer Conformance Test Suite structure is outlined in Table 1.

Data Link Layer Test Groups	Test State Abbreviation	Test Group Name	Current State of IUT
DL1	DP	Disconnect phase	DISC received and UA or DM transmitted (see clause 4.10)
DL2	LD	Link Disconnection phase	DISC transmitted from any phase (see clause 4.11)
DL3	LS	Link Set-up phase	SABM transmitted from DP (see clause 4.11)
DL4	IT	Information Transfer phase	SABM received and UA transmitted, or SABM transmitted and UA received, while in DP or IT phase
DL5	FR	Frame Reject condition	FRMR transmitted from IT phase (see clause 4.10)
DL6	BY	IUT Busy condition	RNR transmitted from IT phase (see clause 4.10 and 4.11)
DL7	SR	Sent Reject condition	REJ transmitted from IT phase
DL8	SP	System Parameters and Error Recovery	See note below

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### Note:

Test Group DL8 tests the setting of the system parameters:

- T1 Retransmission timer;
- N2 Maximum number of attempts by IUT to complete a transmission.

The setting of maximum established length and k (window size) are tested under test group DL4.

# 4.2 Data link layer test groups and subgroups

The first seven test groups shown in Table 1, called Data Link Layer Test Groups DL1 to DL7, are Sprot 888 reg and Tabular Combined Notation (TTCN). vided to test the interactive capability of the dulibinandar abstract test suite complies with ISO/IEC 9646-3 for every phase. The test groups are further divided into TICN GR 10 The test realizer shall comply with the three subgroups according to the definitions in clause 3.4. These are as follows:

- Subgroup 1 involves those test cases where the tester transmits a proper frame.
- Subgroup 2 involves those test cases where the tester transmits an improper frame.
- Subgroup 3 involves those test cases where the tester transmits an inopportune frame.

The eighth test group (DL8) is designed to test the operational correctness of the IUT system parameters listed in Table 1.

# 4.3 Method for conformance testing

The method for conformance testing shall be as defined in ISO/IEC 8882-1.

# 4.4 Test case notation

Clause 5 describes the abstract test suite using the requirements of ISO/IEC 9646-4. In particular, these concern the realization of an Executable Test Suite (ETS) based on the Abstract Test Suite (ATS). Test laboratories running conformance test services for this abstract test suite shall comply with ISO/IEC 9646-5.

The tests described in this test suite may be performed in any order. Test cases are independent of one another. Most of the test cases consist of a preamble followed by a test body and ending with a ver-The preamble consists of the ification sequence. steps described in clause initialization test "Preambles." The verification sequences consists of the final test step described in clause "Verification sequences." In some instances in the test steps, all the possible parameter alternatives for PDUs are not verified, as they do not directly relate to the test purpose.

The preambles shown in this part of ISO/IEC 8882 are examples of how, for different situations, the tester can get the IUT into the desired phase or state. These preambles are not meant to be either a mandatory or exhaustive set of acceptable initialization sequences for the IUT. Other possible preambles may be negotiated between the test laboratory and the client. Table 2 illustrates an abstract test case written in TTCN:

Table 2. Test Ste	ep Dynamic Behavior			
Test Step Name	: TTCN EXAMPLE			
Group	: Example Test Case			
Objective	: An example test step illustrating an abstract test ca	ase in TTCN.		
Default	:			
Comments	:			
			1 10 11 1	

Nr	Label	Behavior Description	Constraints Ref	Verdict	Comments
1		+ preamble_1 [IUT_TYPE = option_1]			1
2		+ preamble_n [IUT_TYPE = option_n]			2
3 4		+ test_body_part_1 + verification_1			
5		I PDU_X			5
6		? PDU_Y [IUT_TYPE = option_2]			6
7		(VARIABLE := 1)			7
8		+ verification_2			
9		+ test_body_part_n			
10		+ verification_n			

### **Detailed Comments**

- The '+' symbol indicates the attachment of a TTCN tree.
- Trees attached at the same level of indentation are alternatives 2
- Event line starting with '!' is a send event in TTCN. 5
- Event line starting with '?' is a receive event in TTCN. A
- 7 The operation ':=' is an assignment in TTCN.

# PREVIE

# 4.5 Preamble

The Preamble of a test case consists of the steps OS required to bring the IUT to the appropriate initial There may be various alternative see state or phase. sequences of test steps, which can be performed in dards/sist/d7eae0e4-1a2a-4724-99adorder to initialize the IUT. The preamble may depend on the test method as well as specific IUT behavior that can be controlled or observed using that method. Therefore, preambles may be different for different IUTs. In order to properly initialize a test case an appropriate preamble has to be used for testing a particular IUT. An inconclusive verdict in the preamble may be the result either of protocol violation or of the fact that the preamble is unsuitable for that particular IUT. Clause "Preambles" gives examples of preambles to be used as a test initialization sequence. Other valid preambles that may be used are a matter of agreement between the test laboratory and its client.

# 4.6 Verification sequence

The conclusion of a test case is conducted in the test sequence called a verification sequence. In most cases the verification sequence depends on the final state in which the IUT is expected to be as a result of a test stimulus. A single test case may have more than one possible verification sequence depending on the actual IUT behavior. Also, like the preamble, the verification sequence may depend on the testing method used or may depend on the IUT. Clause "Verification sequences" gives examples of verifica-

tion sequences to be used as a test conclusion sequence. Other valid verification sequences that may be used are a matter of agreement between the test laboratory and its clients.

## o-jec-4:7821011 initiated actions

The general principles, with respect to IUT initiated actions required by this test suite, are in accordance with ISO/IEC 8882-1. The ability of the IUT to perform these actions, and its ability to initiate the tests containing the actions, are determined by the information provided in the PIXIT.

# 4.8 Acceptable unexpected IUT frames

The test cases in this test suite indicate the frames from the IUT required to satisfy the test purpose. In some cases, particularly in the Information Transfer phase, unexpected frames may be received from the IUT which do not affect the final test verdict.

Acceptable unexpected frames are accepted by the tester without affecting the final test verdict. In the case of RNR, the tester shall suspend the test until the busy condition is cleared (see Table 3, item 7b).

In a controlled environment, DISC and SABM commands and DM responses sent by the IUT are not considered to be acceptable unexpected frames during information transfer tests.

## 4.9 Transient states

A transient state is an unstable state that may preclude satisfactory conduct of tests contained in clauses "Verification of the disconnected phase," "Verification of frame reject condition" and "Verification of IUT busy condition." To conduct tests in these clauses the IUT must be capable of:

- Being forced to establish a particular data link condition or phase as part of the test preamble, by using the LAPB procedures as defined in X.25 standards.
- Maintaining the established condition for a period of time sufficient for the tester to initiate and conduct the required test steps in an orderly and observable manner.
- Arriving at a prescribed, predictable condition or phase for the verification of the test, and maintaining that condition for a time sufficient to record the results from the verification sequence.

## 4.10 Unreachable states

An unreachable state is a state never entered by some IUTs. This may preclude satisfactory conduct of tests contained in clauses "Verification of the IUT link disconnection phase," "Verification of link setup phase" and "Verification of IUT busy condition."

## 4.11 Declarations

The purpose of TTCN declarations is to describe the set of test events and all other attributes to be used in the test suite. For further information on TTCN declarations see ISO/IEC 9646-3.

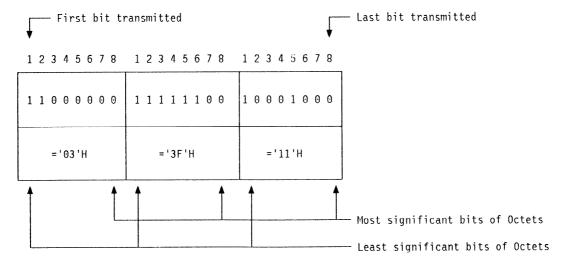
For the X.25 Data Link Layer test suite, the declarations are based on Protocol Data Units (PDUs) defined in OSI Basic Reference Model [ISO/IEC 7498-1] are called "frames" in the X.25 standards. The PDUs are declared with a set of PDU parameters that may be assigned values for the purpose of testing. The PDU constraints (specified in clause "ASN.1 PDU constraint declarations") are the list of values that the PDU parameters must take in a particular test event.

The improper PDUs are declared only for the purpose of use within ISO/IEC 8882. It is recognized that many variations are possible in an improper PDU, all of which may cause the same reaction from the IUT. It is not practical to exhaustively list all these variations. To preserve the flexibility of improper PDU encoding, ISO/IEC 8882 shows some typical examples.

The FCS octets are not shown in the data type declarations in this test suite.

# 4.12 Order of bit transmission

ISO/IEC 888The lorder of bit transmission for the PDUs in the dechttps://standards.iteh.ai/catalog/standards/arations/above/shall7be-asadefined in the X.25 stand-d185b7e505ba/iso-iards/82The order of bit transmission for PDUs in the declarations for ABORT, HEX and FCS\_ERROR is illustrated in the example shown in Figure 2.



NOTE - This example does not show flags, FCS fields, and bits inserted for transparency.

Figure 2 - Example - Hex (String:='033F11'H)

# 4.13 PIXIT proforma

It is essential that the client provide the test laboratory with all the information (in addition to that given in the PICS) that will enable the appropriate test cases to be applied to the IUT. This information is provided in the Protocol Implementation eXtra Information for Testing (PIXIT). This PIXIT proforma is related to and dependent on the Protocol Implementa-

tion Conformance Statement (PICS) proforma which is being developed as an amendment to ISO/IEC 7776.

A mnemonic enclosed in parenthesis, e.g. (N2), indicates the test suite parameter that maps to this PIXIT question.

Item	General Information	Values
	Classification of IUT, select one of ISO_7776, X25_1980, X25_1984, if conformance is claimed to ISO/IEC 7776, X.25_1980 or 1984 respectively. (IUT_TYPE)	Value:
2	The value of k used by IUT. (k)	Value:
3	The value of the maximum established length of the information field of the received I frames. (MEL)	Value:
4	The value of N2 for IUT. (N2)	Value:
5	The value of T1 parameter, in milli-seconds, used by the IUT. (T1_ONE)	Value:
Md	Which MODULO base is used for these tests? (Md)	Value:
Item	Procedural Information	Values
6	IUT will initiate transmission of I frames on entering information transfer tests.	□Yes □No
6a	IUT acknowledges I frames immediately so that it can handle a full window of I frames within timer T1/2. (IUT_ACK)	□Yes □No
7a	IUT can be made to enter the busy condition when required for testing. (IUT_SEND_RNR)	□Yes □No
7 <b>a</b> 1	If yes to 7a, specify the time, in milli-seconds, the NUT will gemain busy.	Value:
7b	Specify if IUT will send RNR after line set up (e.g., this may correspond to a situation where RNR is used while higher level is being/set up). 8882-2-1995	□Yes □No
7b1	If yes to 7b, enter the MAXIMUM time, in milli-seconds, the IUT will be in busy condition. (Tb)	Value;
8	IUT can be made to initiate link disconnection when required for testing. (IUT_SEND_DISC)	□Yes □No
8 <b>a</b>	Is manual intervention required to initiate link disconnection when required for testing.	□Yes □No
8a1	If yes to 8a, specify the time, in milli-seconds.	Value:
9	State the time in milli-seconds the tester must wait before determining that the IUT will not respond to a tester stimulus. This value will be tester parameter Td. Note: $Td < T1$ . (Td)	Value:
10a	IUT can be made to set-up the link when required for testing. (IUT_SETUP_LINK)	□Yes □No
10a1	If yes to 10a, specify PICS item under "Link set-up (reset) procedure" to be used.	PICS item:
10b	IUT can request the tester to set-up the link when required. (TEST_DM)	□Yes □No
11	IUT can maintain the disconnected phase as a stable state for a period of time. (STABLE_DP)	□Yes □No
11a	If yes to 11, specify the time, in milli-seconds, IUT will remain in disconnected phase. During this time period the IUT will not unlaterally send a SABM, DISC, or DM frame.	Value:
12	The IUT can maintain the frame reject condition as a stable state for a period of time. (STABLE_FRMR)	□Yes □No
12a	If yes to 12, specify the time, in milli-seconds, IUT will remain in frame reject condition.	Value:
13a	Upon reaching the disconnected phase, will the IUT reply with DM response to all commands received, and not set up the data link until some operator action is taken. (DMRSP)	□Yes □No

Table 3	(Page 2 of 2). Protocol Implementation eXtra Information for Testing (PIXIT)	
13b	Upon reaching the disconnected phase, will the IUT not respond to any stimulus, and not set up the data link until some operator action is taken. (UNRSP)	□Yes □No
14	Where operator action is required (for implicit send events), specify the maximum time, in seconds, required for the operator to complete the requested action.  (TOPERATOR)	Value:
item	I Frame Information	Values
15	Specify in sequence contents of the information field that the tester is allowed to send to the IUT in information transfer phase. (UDAT)	Frame 1:
	Note: Note that in some tests up to $k + 1$ frames are sent from the tester.	
15a		Frame 2:
15b		Frame 3:
15c		Frame 4:
15d		Frame 5:
15e		Frame 6:
15f		Frame 7:
15g		Frame 8:
16	Specify the i-field for an I frame that is to contain a too long information field. (ULON)	Value:

# 4.14 Classification of IUT

In this test suite the global variable "IUT\_TYPE" is ARD PREVIEW defined. This variable can assume values for ISO/IEC 7776, or X.25-1980, or X.25-1984. A Boolean rds.iteh.ai) expression is used to test this variable before a test event can apply to one specific standard. If this is not 8882-2:1995 done, then that event applies to all three X.25 astand and ards/sist/d7eae0e4-1a2a-4724-99ad-ards.

d185b7e505ba/iso-iec-8882-2-1995

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# 5 TTCN abstract test suite

# 5.1 Test suite overview

Table 4. Test Si	Table 4. Test Suite Structure	
Suite Name	: ISO/IEC 8882-2	
Standards Ref	: ISO/IEC 7776 : 1986	
PICS Ref	: ISO/IEC 7776/DAM1 : 1991	
PIXIT Ref	: ISO/IEC 8882-2	
Test Method(s)	: Remote Embedded Single Layer	
Comments		

Test Group Reference		Test Group Reference Selection Ref Test Group Objective		Page Nr	
DL1/		DP_STABLE	Verification of the Disconnected Phase		
DL1/DL1_PROPER/			Proper frames	63	
DL1/DL1_IMPROPER/			Improper frames	65	
DL1/DL1_INOPPORTUNE/			Inopportune frames	70	
DL2/		SEND_DISC	Verification of IUT Initiated Link Disconnection Phase		
DL2/DL2_PROPER/			Proper frames	77	
DL2/DL2_IMPROPER/			Improper frames	80	
DL2/DL2_INOPPORTUNE/		NOT_CCITT_80	Inopportune frames	85	
DL3/		SEND_SABM	Verification of Link Set-up Phase		
DL3/DL3_PROPER/			Proper frames	90	
DL3/DL3_IMPROPER/			Improper frames	92	
DL3/DL3_INOPPORTUNE/		NOT_CCITT_80	Inopportune frames	97	
DL4/			Verification of Information Transfer Phase		
DL4/DL4_PROPER/			Proper frames	102	
DL4/DL4_IMPROPER/	Pal (		Improper frames	110	
DL4/DL4_INOPPORTUNE/	iTeh S	IANDA	Inopportune frames	119	
DL5/		FRMR_STABLE	Verification of Frame Reject Condition		
DL5/DL5_PROPER/		(standar	Proper frames	121	
DL5/DL5_IMPROPER/		(Stantaar)	Improper frames	122	
DL5/DL5_INOPPORTUNE/ DL6/		SEND RNR	Inopportune frames  Verification of IUT Busy Condition	128	
DL6/DL6 PROPER/		ISO/IEC 8	Proper frames	134	
DL6/DL6_FROPER/	1 // . 1 1			138	
DL6/DL6_INOPPORTUNE/	https://standards.	iteh.ai/catalog/stand	ardmgroper/trames4-1a2a-4724-99ad- Inopportune frames	147	
DL7/		d185b7e505ba/iso	Verification of Sent Reject Condition	147	
DL7/DL7 PROPER/			Proper frames	149	
DL7/DL7_IMPROPER/			Improper frames	153	
DL7/DL7 INOPPORTUNE/			Inopportune frames	162	
DL8/			System Parameters and Error Recovery tests	163	